

Buffers/drivers

FAST 74F655A, 74F656A

74F655A Octal buffer/driver with parity, inverting (3-State); 74F656A Octal buffer/driver with parity, non-inverting (3-State)

FEATURES

- Significantly improved AC performance over 'F655 and 'F656
- High impedance NPN base inputs for reduced loading ($40\mu A$ in High and Low states)
- Ideal in applications where high output drive and light bus loading are required (I_{OL} is $40\mu A$ vs FAST std of $600\mu A$)
- 'F655A combines 'F240 and 'F280A functions in one package
- 'F656A combines 'F244 and 'F280A functions in one package
- 'F655A Inverting
- 'F656A Non-Inverting
- 3-state outputs sink $64mA$ and source $15mA$
- 24-pin plastic Slim DIP (300mil) package
- Inputs on one side and outputs on the other side simplifies PC board layout
- Combined functions reduce part count and enhance system performance
- Industrial temperature range available (-40°C to +85°C)

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F655A	6.5ns	64mA
74F656A	6.5ns	64mA

ORDERING INFORMATION

PACKAGES	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$ $T_{amb} = 0^\circ C$ to $+70^\circ C$	INDUSTRIAL RANGE $V_{CC} = 5V \pm 10\%$ $T_{amb} = -40^\circ C$ to $+85^\circ C$
24-Pin Plastic Slim DIP (300mil)	N74F655AN, N74F656AN	I74F655AN, I74F656AN
24-Pin Plastic SOL	N74F655AD, N74F656AD	I74F655AD, I74F656AD

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
D0-D7	Data inputs	2.0/0.066	$40\mu A/40\mu A$
PI	Parity input	1.0/0.033	$20\mu A/20\mu A$
OE0, OE1, OE2	Output Enable inputs (active Low)	1.0/0.033	$20\mu A/20\mu A$
Σ_E , Σ_O	Parity outputs	750/106.7	$15mA/64mA$
Q0-Q7	Data outputs ('F655A)	750/106.7	$15mA/64mA$
Q0-Q7	Data outputs ('F656A)	750/106.7	$15mA/64mA$

NOTE:

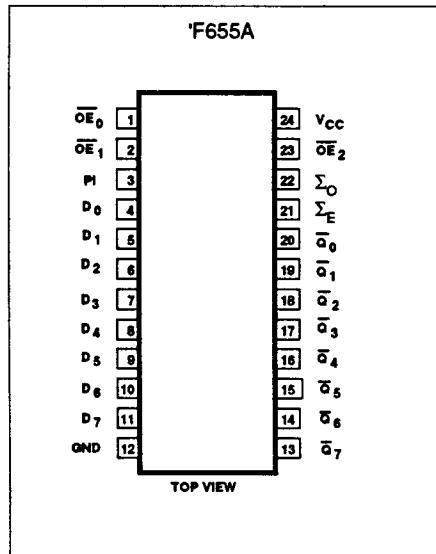
One (1.0) FAST Unit Load is defined as: $20\mu A$ in the High state and $0.6mA$ in the Low state.

DESCRIPTION

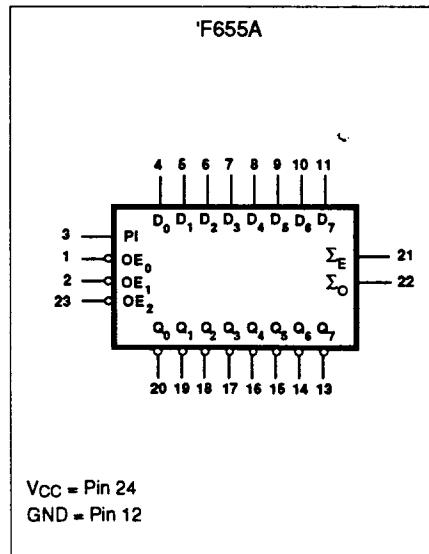
The 74F655A and 74F656A are octal buffers and line drivers with parity generation/checking designed to be employed as memory address drivers,

clock drivers, and bus-oriented transmitters/receivers. These parts include parity generator/checker to improve PC board density.

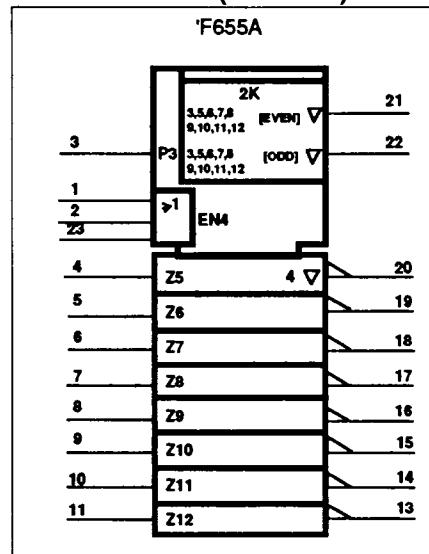
PIN CONFIGURATION



LOGIC SYMBOL



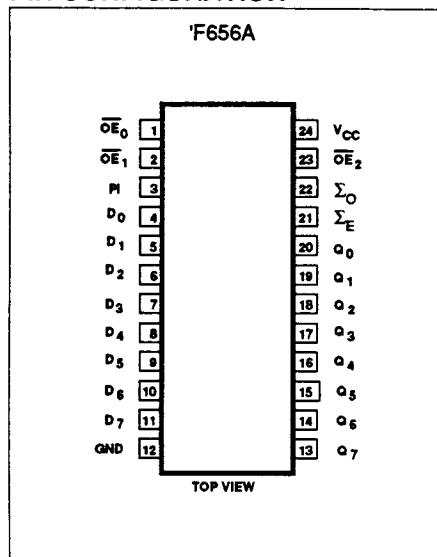
LOGIC SYMBOL(IEEE/IEC)



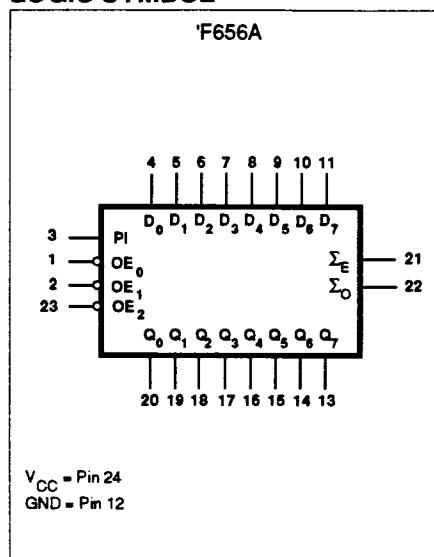
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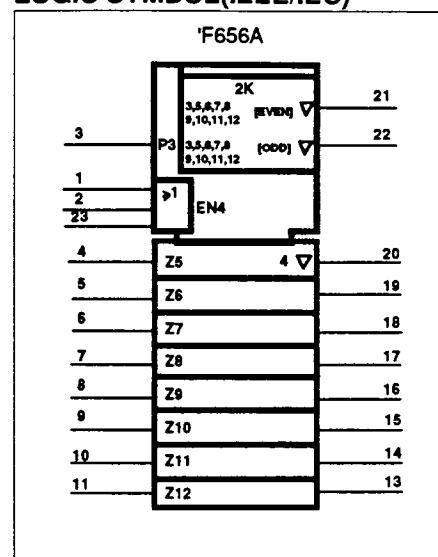
PIN CONFIGURATION



LOGIC SYMBOL



LOGIC SYMBOL(IEEE/IEC)



FUNCTION TABLE

INPUTS				OUTPUTS	
				'F655A	'F656A
<u>OE0</u>	<u>OE1</u>	<u>OE2</u>	Dn	<u>Qn</u>	<u>Qn</u>
L	L	L	L	H	L
L	L	L	H	L	H
H	X	X	X	Z	Z
X	H	X	X	Z	Z
X	X	H	X	Z	Z

H = High voltage level

L = Low voltage level

X = Don't care

Z = High impedance "off" state

FUNCTION TABLE for PARITY OUTPUTS

INPUTS	OUTPUTS	
Number of inputs High (PI, D0-D7)	ΣE	ΣO
Even 0, 2, 4, 6, 8	H	L
Odd 1, 3, 5, 7, 9	L	H
Any <u>OE</u> n=High	Z	Z

H = High voltage level

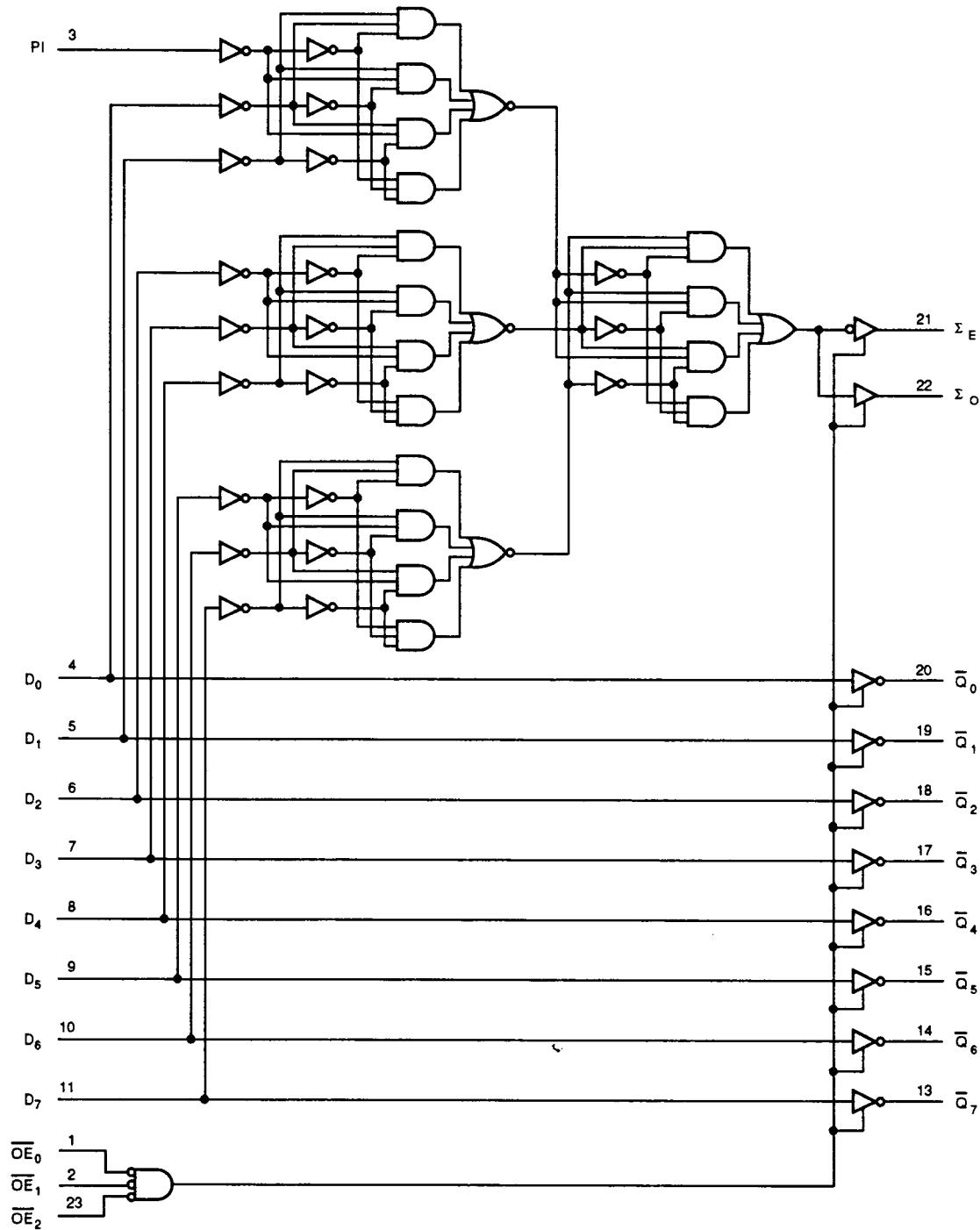
L = Low voltage level

Z = High impedance "off" state

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LOGIC DIAGRAM for 'F655A

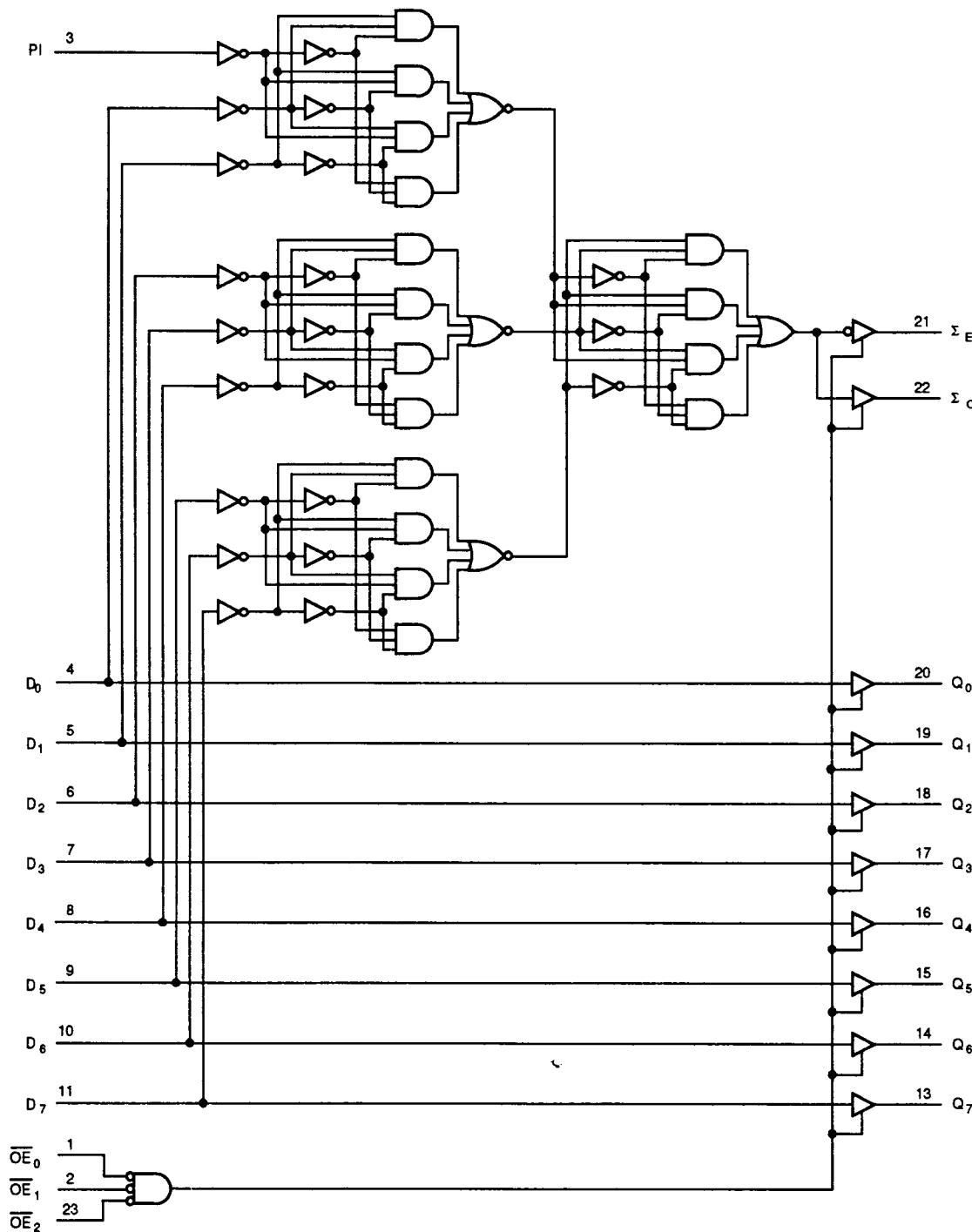


V_{CC} = Pin 24
GND = Pin 12

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LOGIC DIAGRAM for 'F656A



V_{cc} = Pin 24
GND = Pin 12

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ABSOLUTE MAXIMUM RATINGS (Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	-0.5 to +7.0	V
V _{IN}	Input voltage	-0.5 to +7.0	V
I _{IN}	Input current	-30 to +5	mA
V _{OUT}	Voltage applied to output in High output state	-0.5 to +V _{CC}	V
I _{OUT}	Current applied to output in Low output state	128	mA
T _{amb}	Operating free-air temperature range	Commercial range	0 to +70
		Industrial range	-40 to +85
T _{STG}	Storage temperature	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V _{CC}	Supply voltage	4.5	5.0	5.5	V
V _{IH}	High-level input voltage	2.0			V
V _{IL}	Low-level input voltage			0.8	V
I _{IK}	Input clamp current			-18	mA
I _{OH}	High-level output current			-15	mA
I _{OL}	Low-level output current			64	mA
T _{amb}	Operating free-air temperature range	Commercial range	0	70	°C
		Industrial range	-40	85	°C

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DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹			LIMITS			UNIT	
					Min	Typ ²	Max		
V_{OH}	High-level output voltage	$V_{CC} = \text{MIN}$, $V_{IL} = \text{MAX}$, $V_{IH} = \text{MIN}$	$I_{OH} = -3\text{mA}$	$\pm 10\%V_{CC}$	2.4			V	
			$I_{OH} = -15\text{mA}$	$\pm 5\%V_{CC}$	2.7	3.3		V	
			$I_{OH} = -15\text{mA}$	$\pm 10\%V_{CC}$	2.0			V	
V_{OL}	Low-level output voltage	$V_{CC} = \text{MIN}$, $V_{IL} = \text{MAX}$, $V_{IH} = \text{MIN}$	$I_{OL} = 64\text{mA}$	$\pm 10\%V_{CC}$			0.55	V	
				$\pm 5\%V_{CC}$		0.42	0.55	V	
V_{IK}	Input clamp voltage	$V_{CC} = \text{MIN}$, $I_I = I_{IK}$				-0.73	-1.2	V	
I_I	Input current at maximum input voltage	$V_{CC} = 0.0\text{V}$, $V_I = 7.0\text{V}$					100	μA	
I_{IH}	High-level Input current	Commercial range	Dn	$V_{CC} = \text{MAX}$, $V_I = 2.7\text{V}$			40	μA	
			PI, <u>QEn</u>				20	μA	
		Industrial range	Dn				80	μA	
			PI, <u>QEn</u>				40	μA	
I_{IL}	Low-level input current	Dn	$V_{CC} = \text{MAX}$, $V_I = 0.5\text{V}$				-40	μA	
		PI, <u>QEn</u>				-20	μA		
I_{OZH}	Off-state output current High-level voltage applied	$V_{CC} = \text{MAX}$, $V_O = 2.7\text{V}$					50	μA	
I_{OZL}	Off-state output current Low-level voltage applied	$V_{CC} = \text{MAX}$, $V_O = 0.5\text{V}$					-50	μA	
I_{OS}	Short-circuit output current ³	$V_{CC} = \text{MAX}$			-100		-225	mA	
I_{CC}	Supply current (total)	I_{CCH}	$V_{CC} = \text{MAX}$			50	80	mA	
		I_{CCL}				78	110	mA	
		I_{CCZ}				83	90	mA	

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at $V_{CC} = 5\text{V}$, $T_{amb} = 25^\circ\text{C}$.
- Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

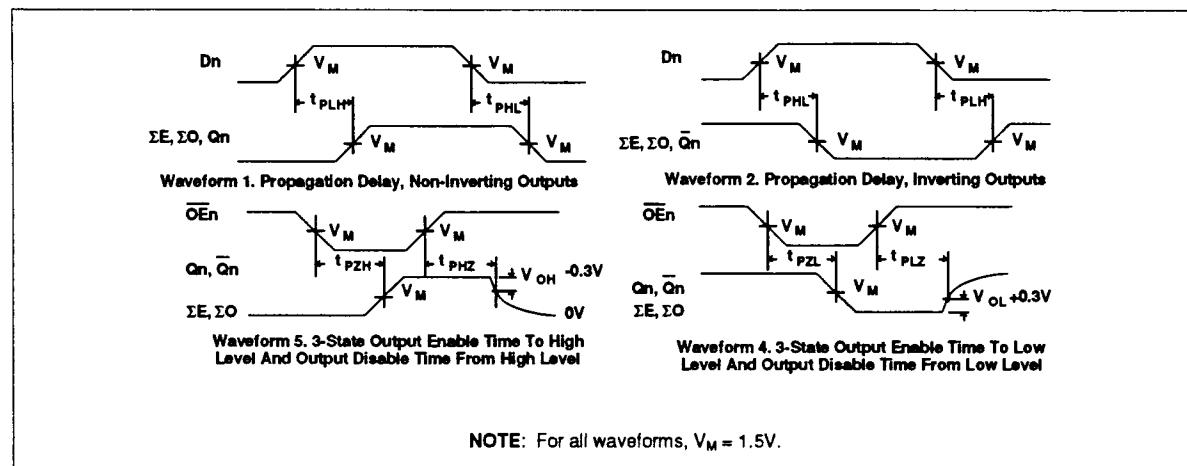
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AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT		
			$T_{amb} = +25^\circ C$			$T_{amb} = 0^\circ C \text{ to } +70^\circ C$		$T_{amb} = -40^\circ C \text{ to } +85^\circ C$			
			$V_{CC} = 5V$	$C_L = 50pF$	$R_L = 500\Omega$	$V_{CC} = 5V \pm 10\%$	$C_L = 50pF$	$R_L = 500\Omega$			
t_{PLH}	Propagation delay D_n to Q_n	'F655A	Waveform 2	2.0 1.0	4.5 2.5	6.5 4.0	2.0 1.0	7.5 4.5	2.0 1.0	8.5 5.5	ns
t_{PHL}	Propagation delay D_n to Q_n	'F656A	Waveform 1	2.0 2.5	4.0 5.5	6.5 7.0	2.0 2.5	7.0 7.5	2.0 2.5	8.0 9.0	ns
t_{PLH}	Propagation delay D_n to $\Sigma E, \Sigma O$		Waveform 1, 2	5.5 5.5	10.0 11.0	13.0 14.5	5.5 5.5	14.0 16.5	4.5 5.5	16.5 18.0	ns
t_{PZH}	Output Enable time to High or Low level		Waveform 3 Waveform 4	3.5 4.0	7.0 8.0	10.5 11.0	3.5 4.0	11.5 12.0	3.0 4.0	13.0 13.5	ns
t_{PLZ}	Output Disable time from High or Low level		Waveform 3 Waveform 4	1.5 2.0	4.5 5.0	8.0 8.0	1.5 2.0	9.0 9.0	1.5 1.5	10.0 10.0	ns

AC WAVEFORMS



TEST CIRCUIT AND WAVEFORMS

